

# *Radiation damage studies in LGAD detectors from recent CNM and FBK runs*

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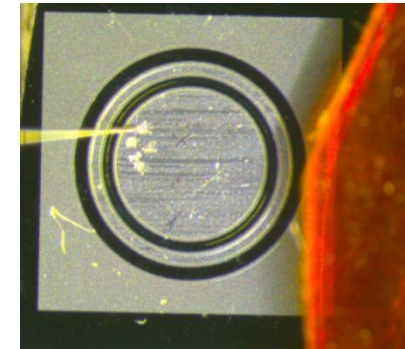
*(a) Jožef Stefan Institute, Ljubljana*

*(b) CNM, Barcelona*

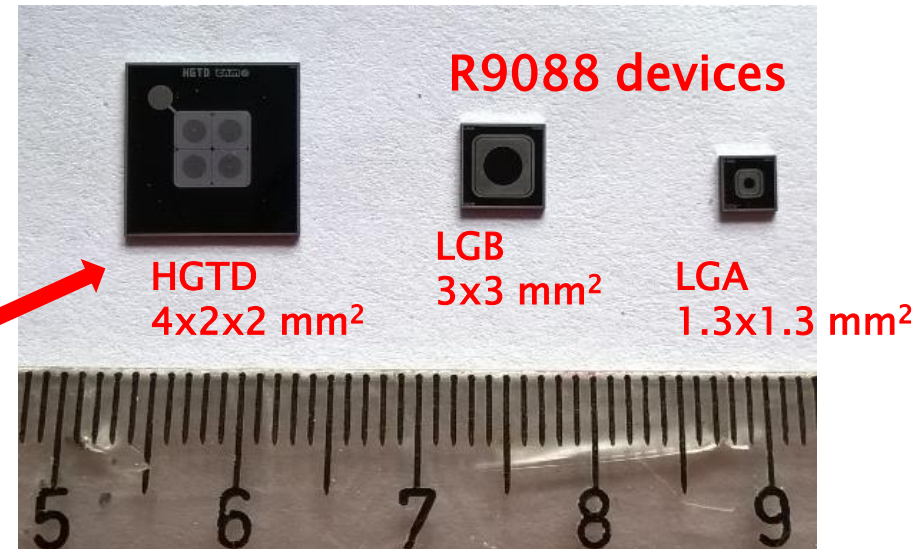
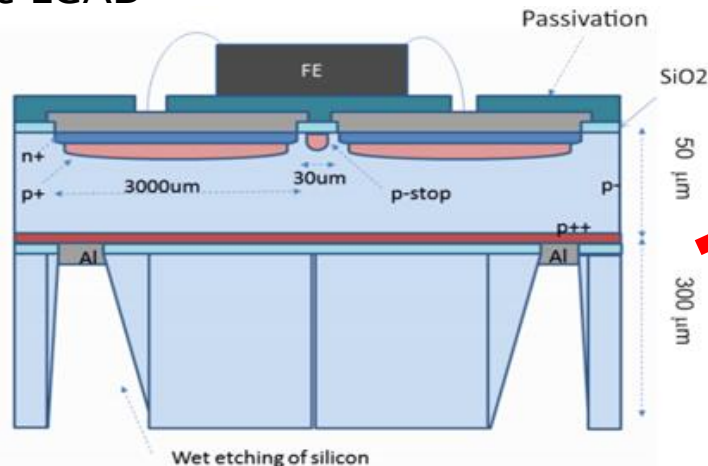
*(c) IFAE, Barcelona*

# CNM devices under study

- ▶ **CNM Run 6827** – 2 years old run (Epitaxial devices, 100  $\Omega\text{cm}$ , 50  $\mu\text{m}$  thick)
  - LGAD samples of low boron concentration in multiplication layer – gain of 7 reached only at high bias voltages
  - Control PIN samples with no multiplication layer
  - Excellent high voltage tolerance
- ▶ **CNM Run 9088** (SOI devices, high-resistivity, 45  $\mu\text{m}$  thick)
  - Three different multiplication layer doping concentrations
    - W3 – Dose =  $1.8\text{e}13 \text{ cm}^{-2}$
    - W5 and W7 – dose =  $1.9\text{e}13 \text{ cm}^{-2}$  (most studied)
    - W11 – Dose =  $2.0\text{e}13 \text{ cm}^{-2}$
  - Three different device structures
  - Control PIN diodes produced along the LGAD

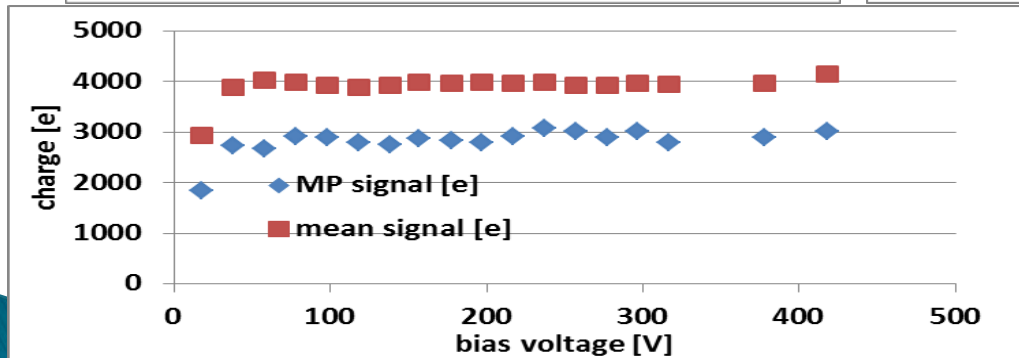
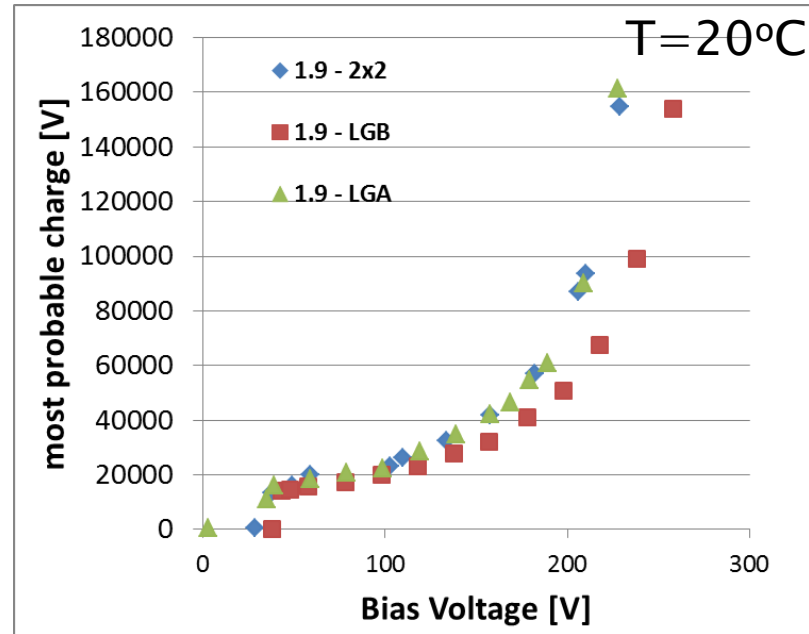
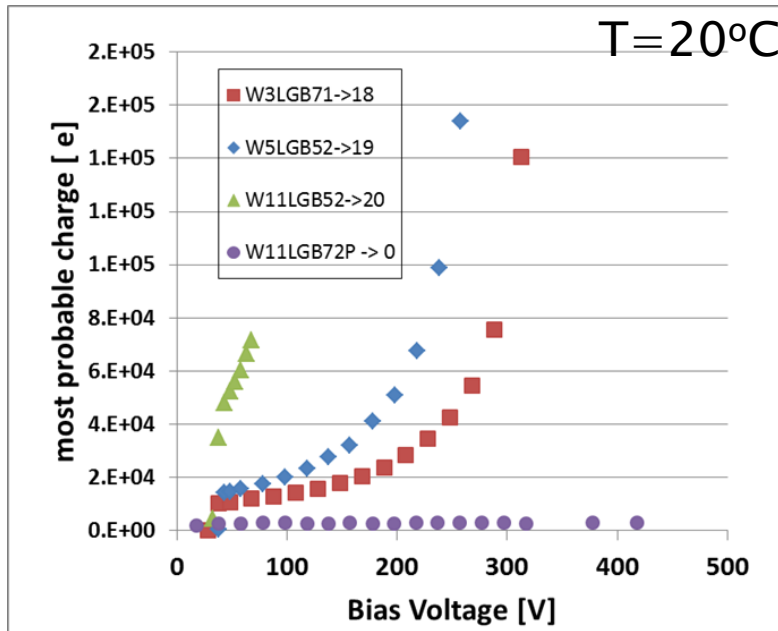


**R6827 device**



# Non-irradiated devices CNM-R9088

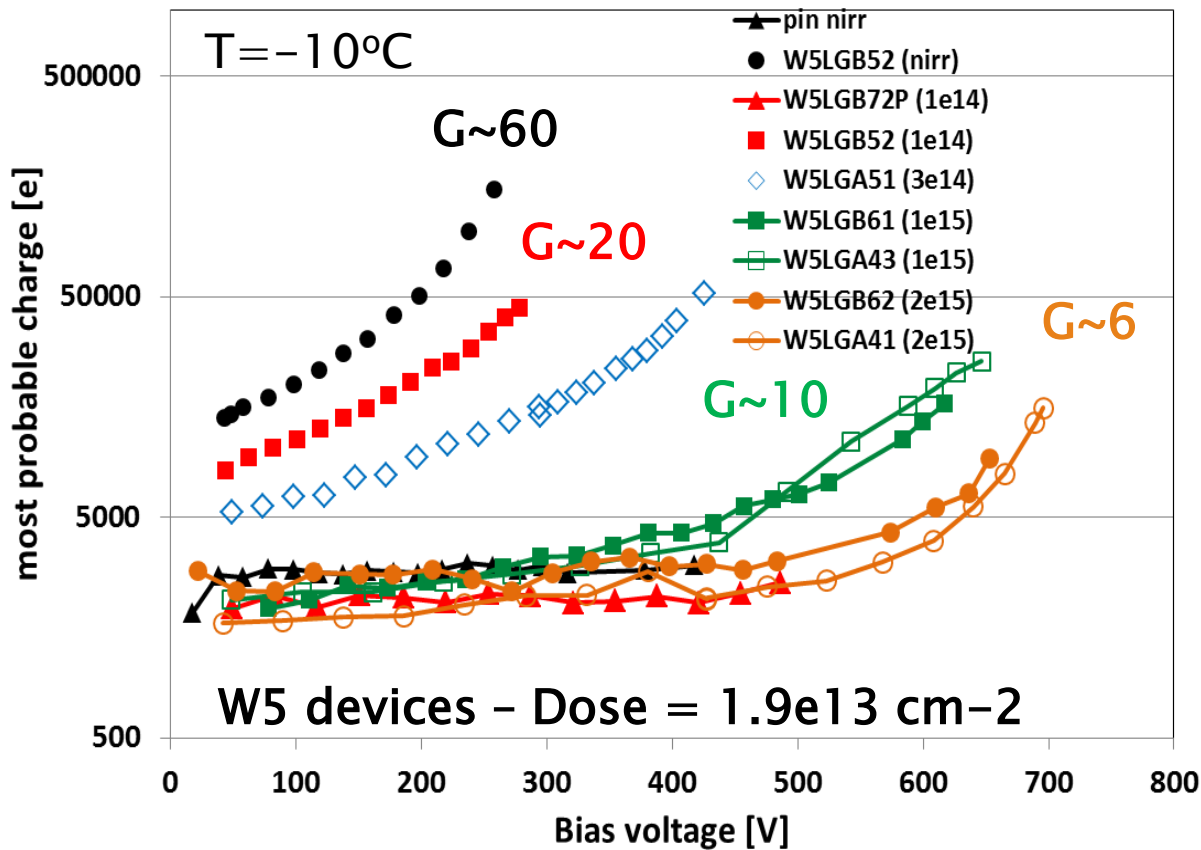
- ▶ Similar device performance regardless of the device type
- ▶ Typical break down in CCE measurements ~300 V (W3), ~260 V(W5) and 90V (W11)



- Most probable signal ~2800 e for non-irradiated detector - 45  $\mu\text{m}$  thick
- Ratio most probable/mean=0.7 - slightly less was expected.

# Signal/gain after neutron irradiations(R9088)

- Gain degrades, but follows the expectations
- “Breakdown” of the device is shifting to higher bias voltages with irradiation for W5



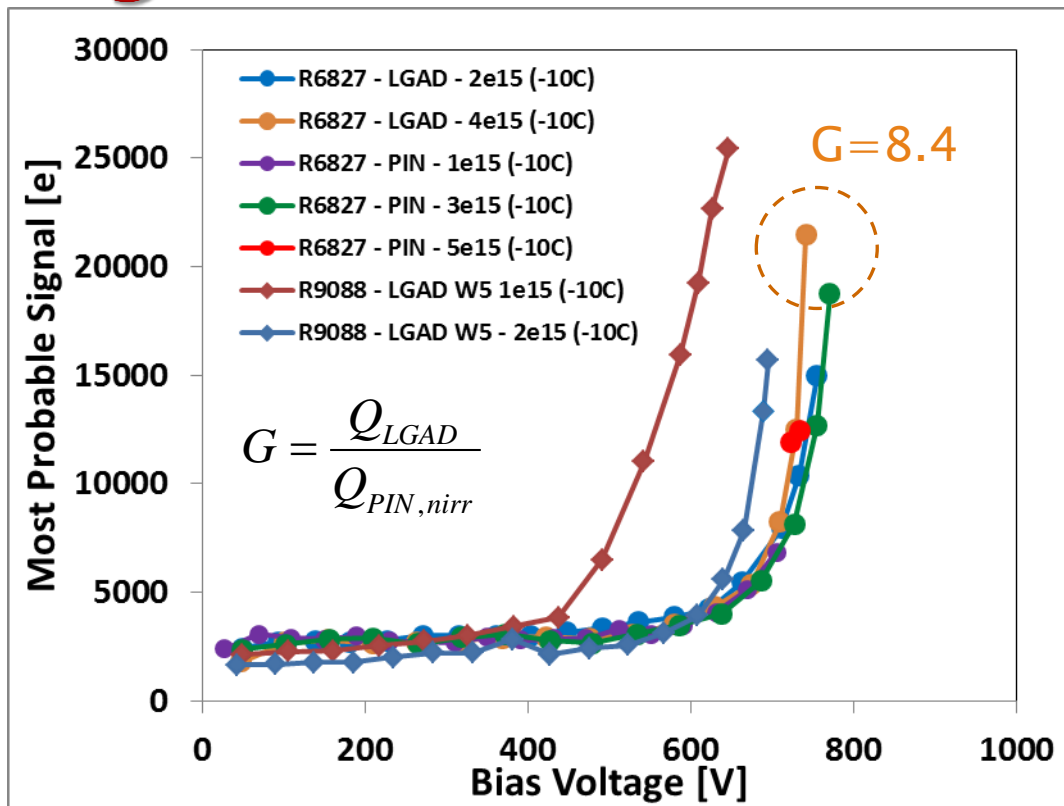
1.) for  $\Phi_{eq} < 1e15 \text{ cm}^{-2}$  effective acceptor removal in multiplication layer reduces the gain, which appears as soon as the multiplication layer is depleted.

2.) Smaller  $N_{eff}$  in multiplication layer leads to smaller slope of the Q-V plot.

3.) at fluences of  $1e15-2e15 \text{ cm}^{-2}$  the multiplication is visible only at higher bias voltages – up to few 100 V collected charge similar to pin diode – the difference between LGAD and PIN becomes small.



# Signal after irradiation for thin LGADs



The last point is always taken just before the detector exhibits a “soft break down”:

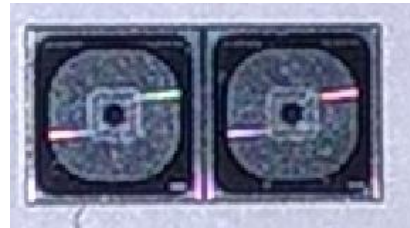
- Irradiation shifts the breakdown voltage to higher values.
- The rise of the charge is associated with the rise of the current and noise (system dependent) which could be kept under control by cooling and cell size
- Note that  $\langle E \rangle \sim 15 \text{ V}/\mu\text{m}$

- ▶ LGAD are advantageous for high gain device up to  $2e15 \text{ cm}^{-2}$
  - ▶ At high fluences  $\Phi > 2e15 \text{ cm}^{-2}$  the behavior is the same for all samples:
    - Regardless of initial doping concentration
    - Regardless of  $p^+$  layer doping (acceptor removal is almost complete)
    - Regardless of annealing behavior (needs to be verified by several samples – so far PIN only).
- It seems that at high enough fluences the performance doesn't degrade anymore – in accordance with predictions (talk at 28<sup>th</sup> RD workshop in Torino)

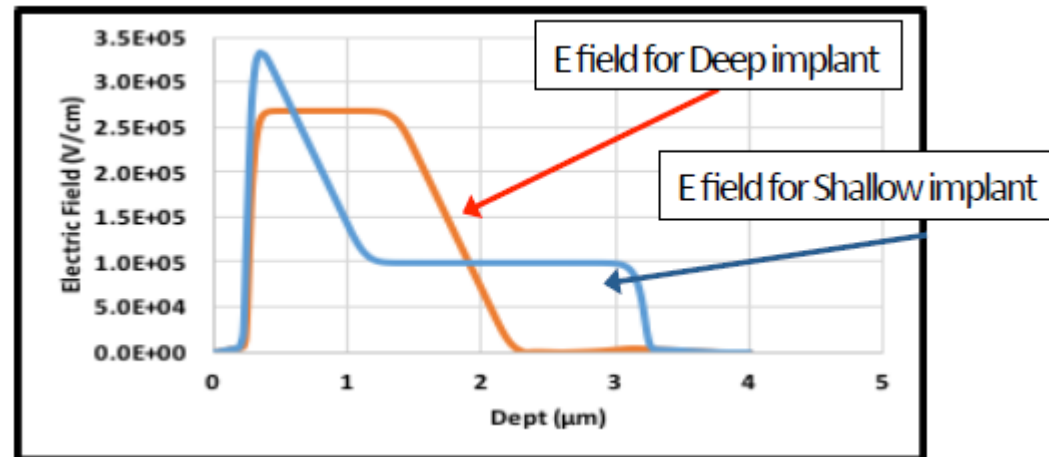
# FBK sensors

see also talk from Roberto and Marco

- ▶ 1<sup>st</sup> FBK LGAD run
- ▶ Geometry
  - 300  $\mu\text{m}$  thick detectors
  - Small 0.5  $\text{mm}^2$
  - Multi guard ring structure – high break down voltages achieved
  - Not all small diodes were diced (multiple samples)
- ▶ Several splits in p+ layer doping concentration
- ▶ Two wafers studies : W3 and W10
  - LGAD of different gains for W10 (Split 4), W3(Split 2)
  - No-gain diode for reference

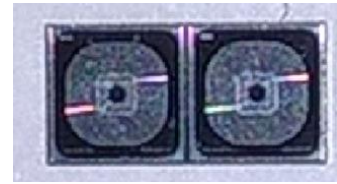
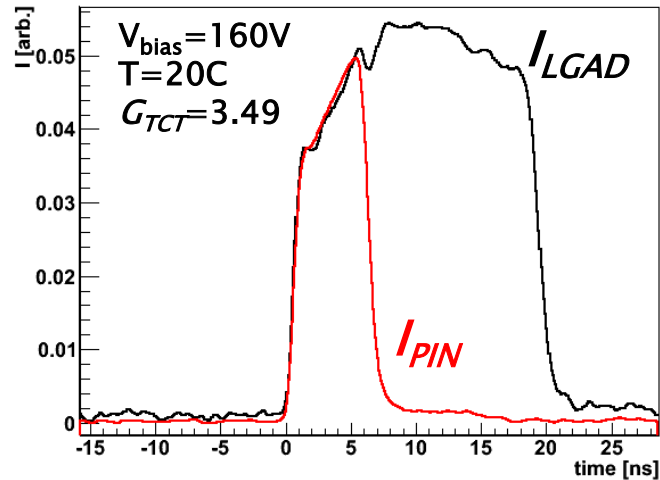
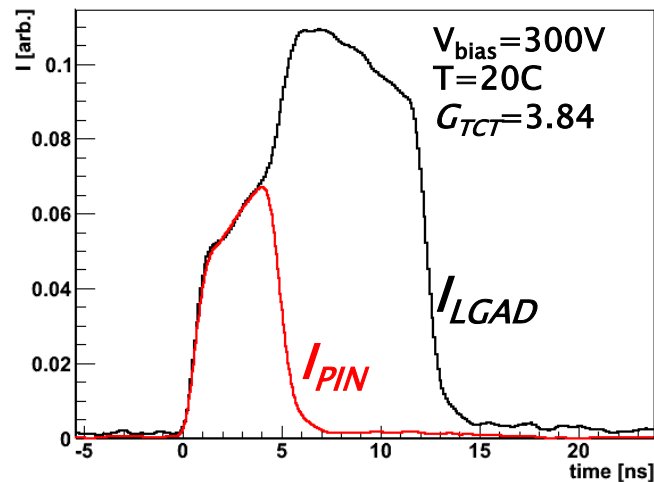


Is such profile more/less radiation hard?

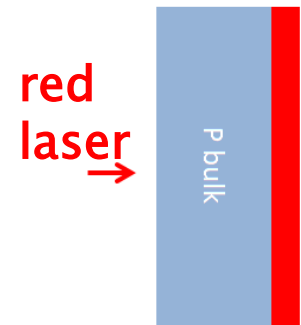


# FBK TCT measurements – pulses & gain

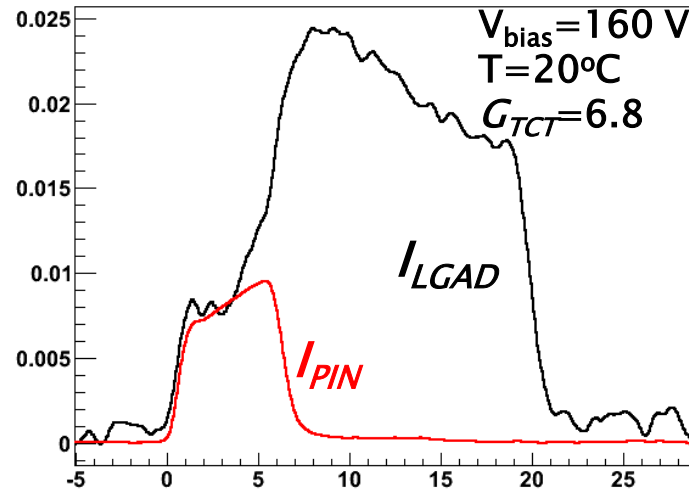
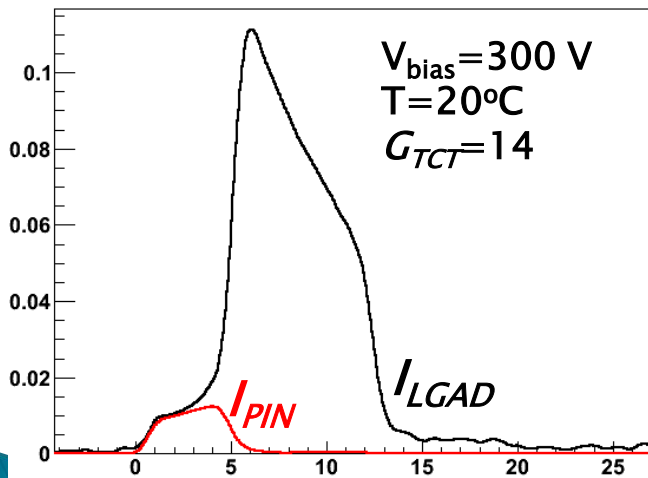
## W3 – wafer



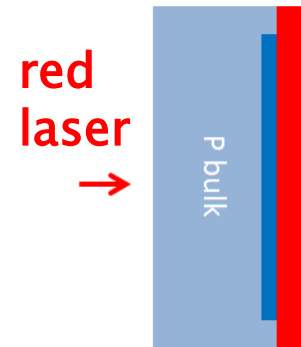
PIN diode



## W10 – wafer

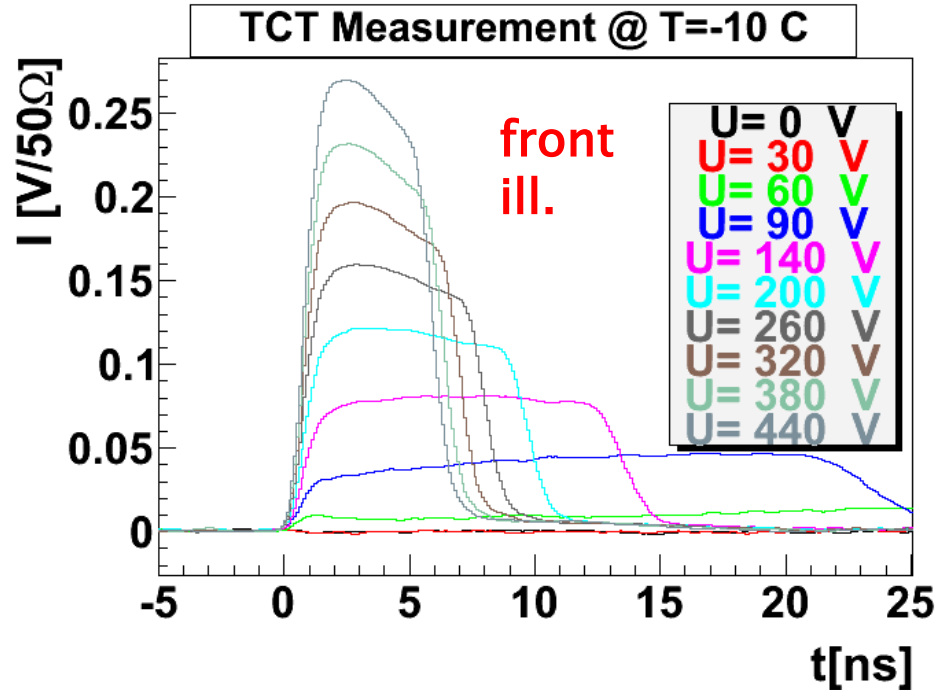
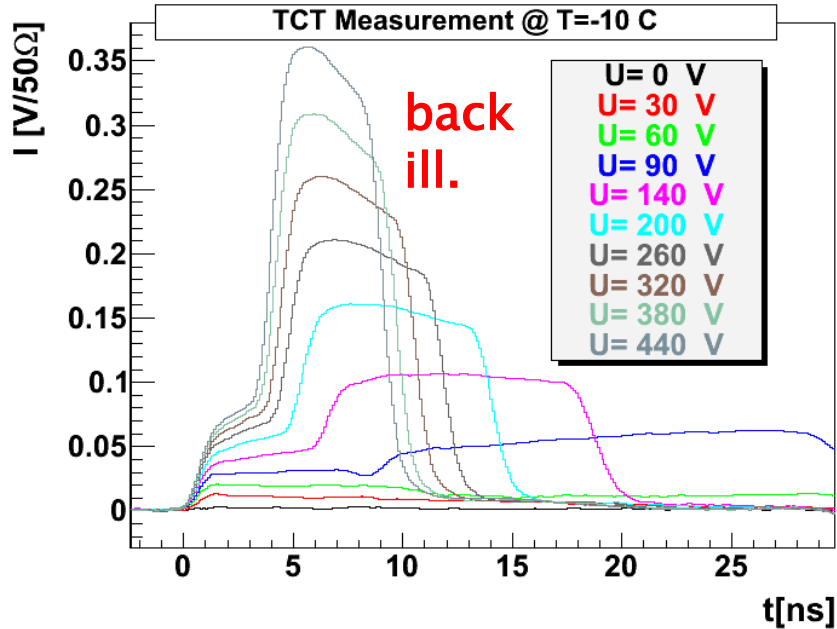


LGAD diode

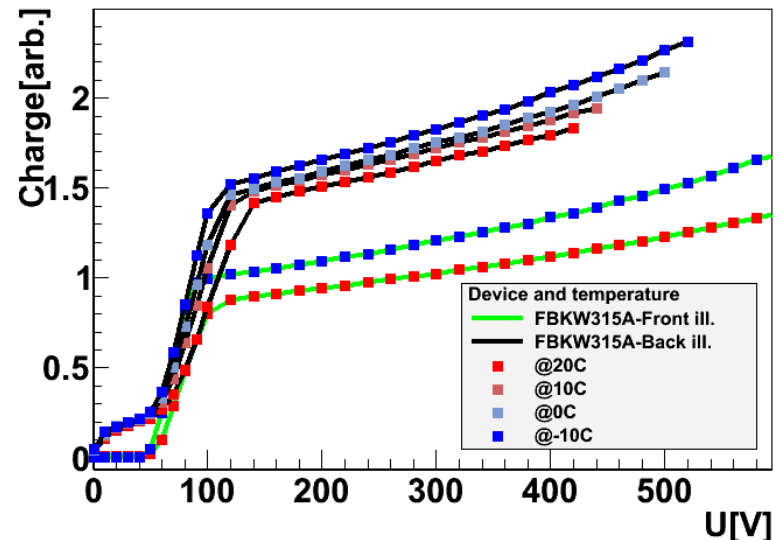


$$G = Q_{LGAD} / Q_{PIN}$$

# TCT (non-irradiated W3 samples)

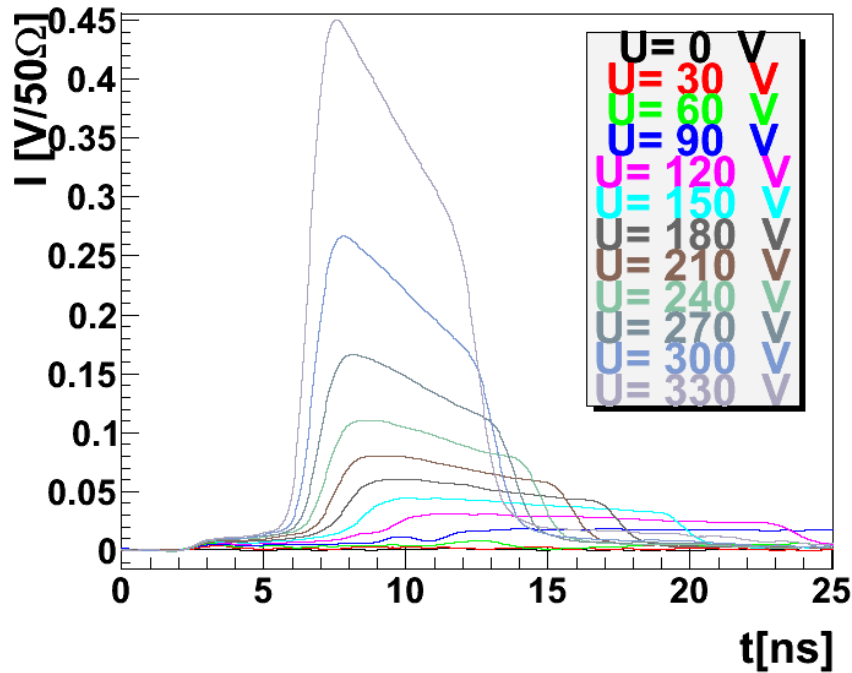


- ▶ The space charge seems to change as a function of voltage
  - At lower voltages the space charge seems to **be positive** (see the slope of the charge)
  - At higher voltages the space charge seems to **be negative**
- ▶ Also seen in Q-V.

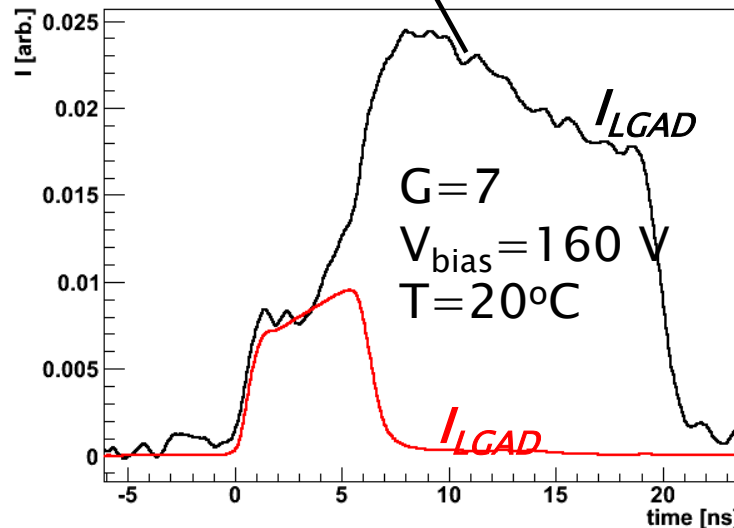
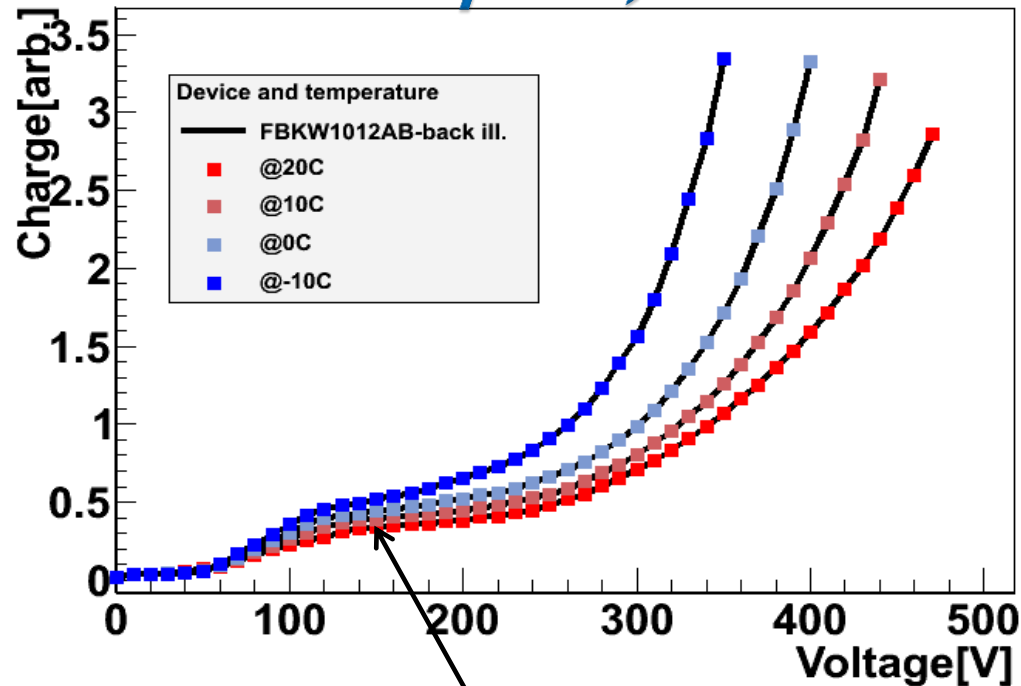




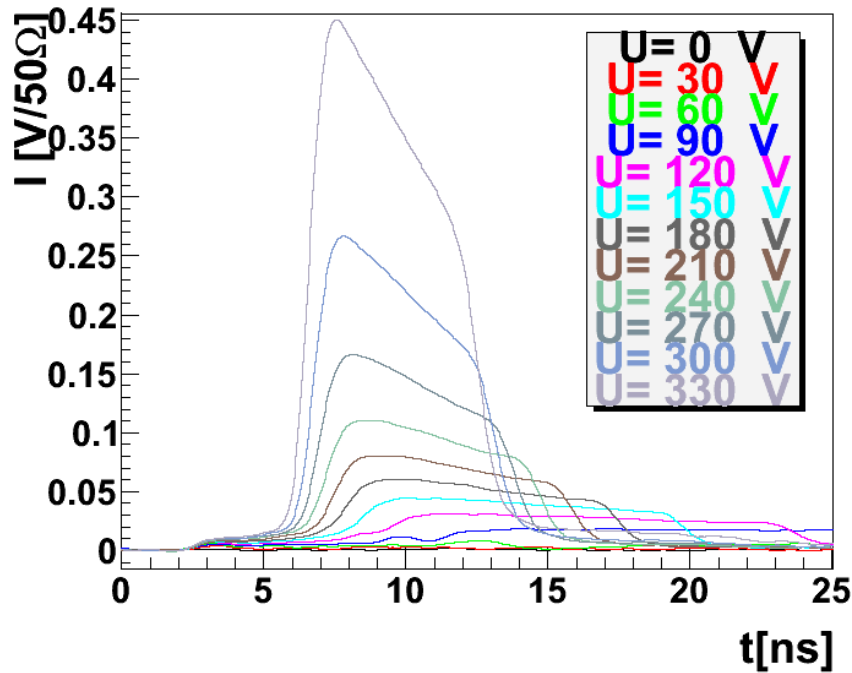
# TCT (non-irradiated W10 samples)



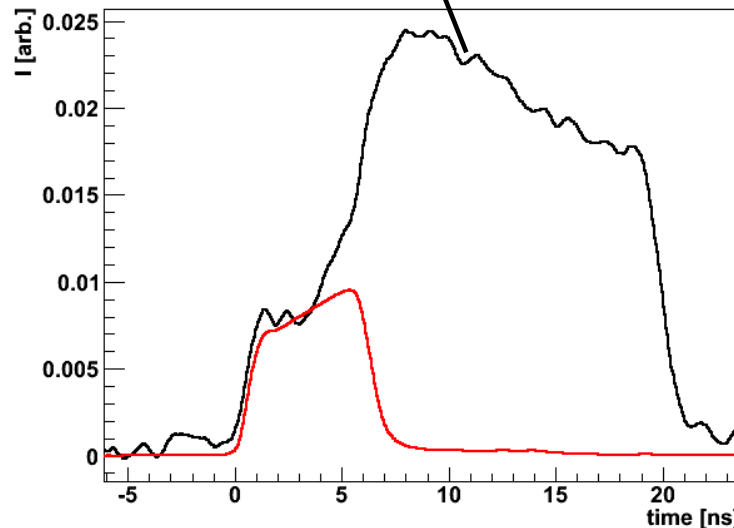
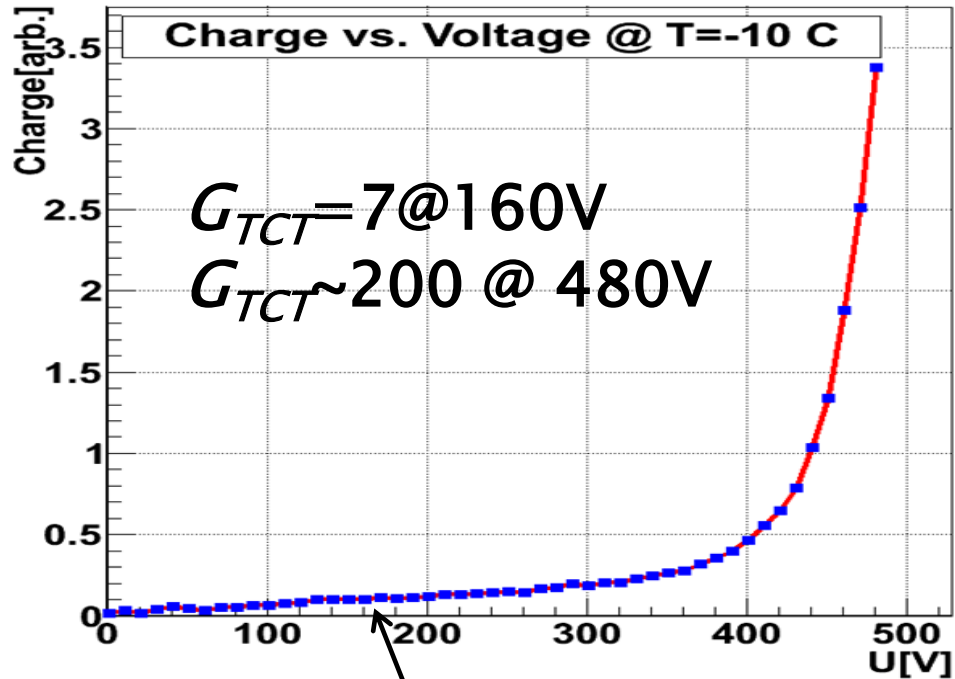
- ▶ Huge gain for W10;  $G > 100$
- ▶ Same observation of space charge changing with bias voltage
- ▶ large gain  $\rightarrow$  large temperature dependence



# TCT (non-irradiated W10 samples)

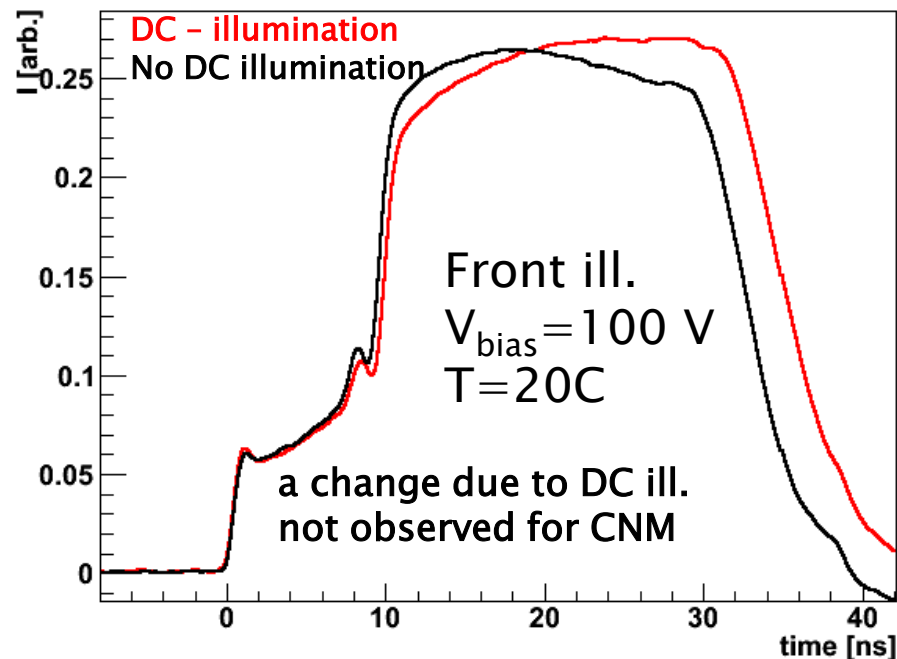
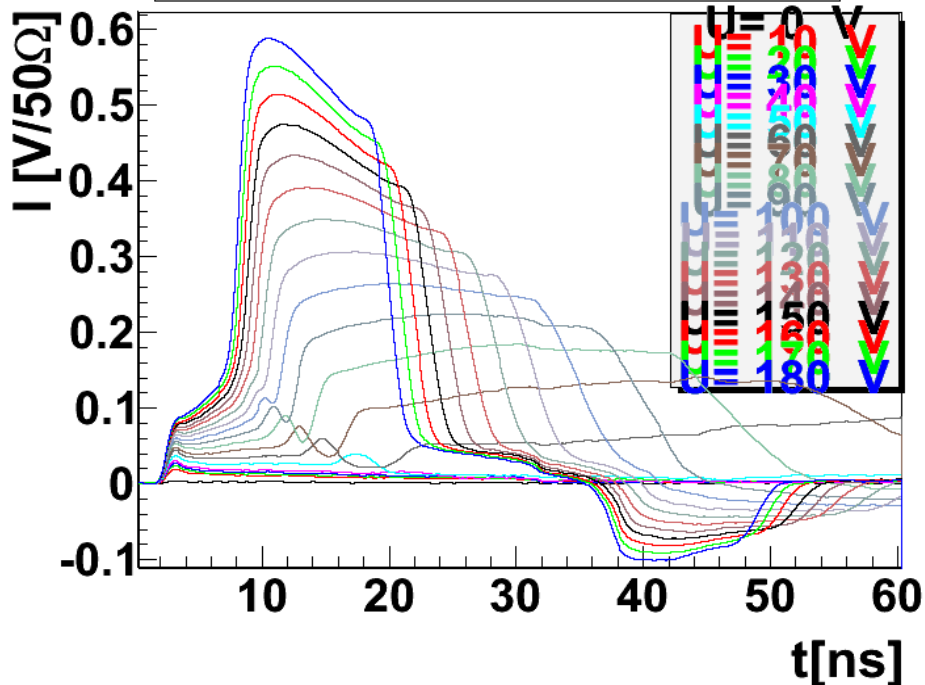


- ▶ Huge gain for W10;  $G > 100$
- ▶ Same observation of space charge changing with bias voltage
- ▶ large gain  $\rightarrow$  large temperature dependence



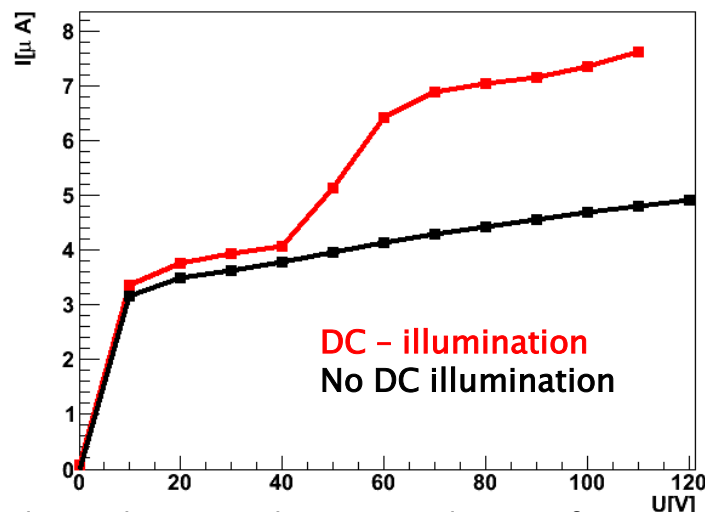
# TCT for W10 – changes in space charge

TCT Measurement @ T=+20 C

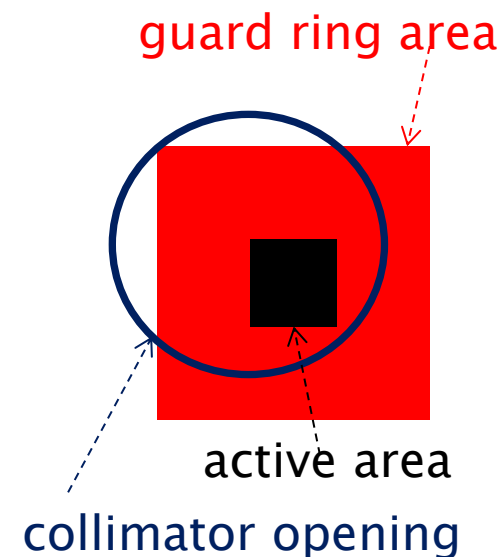
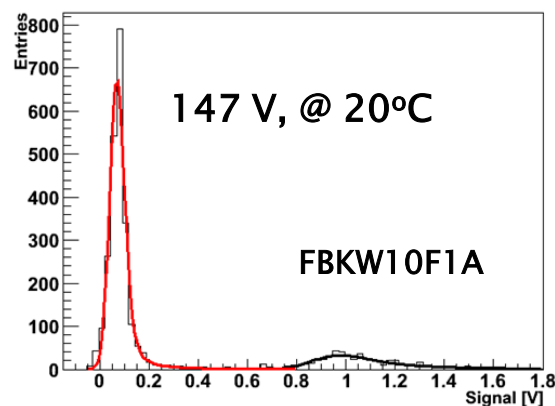
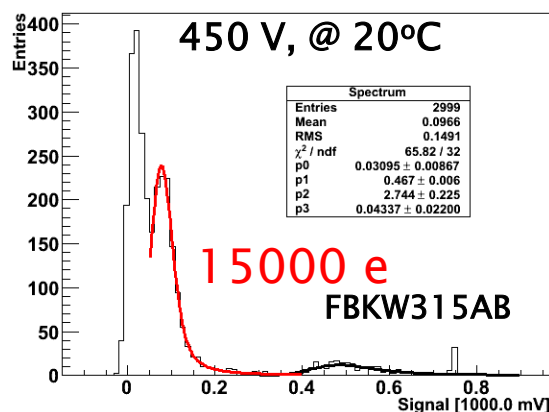
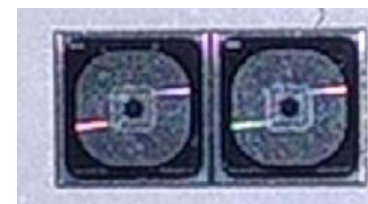
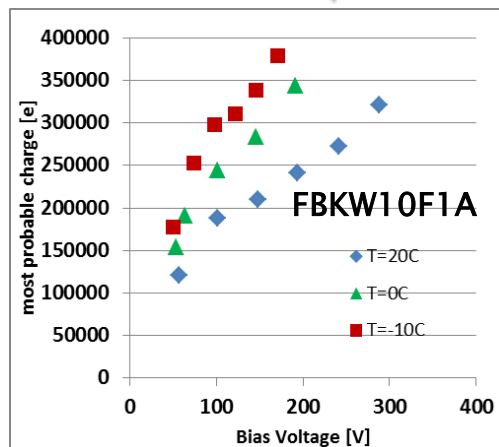
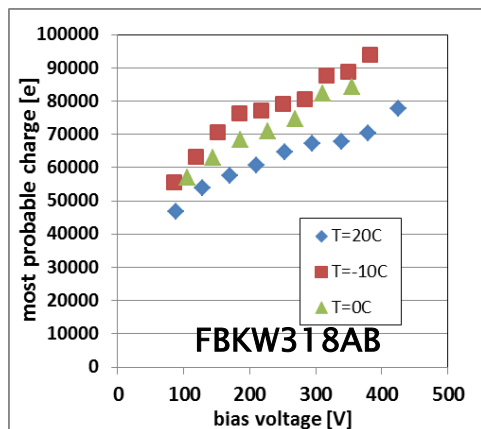


Several features not really understood:

- ▶ Sensitivity to DC illumination (not seen in CNM samples) – indication of deep defects?
- ▶ Deep defects would also explain changes of space charge with voltage
- ▶ Unknown features in the signal for W10 – unclear if real physics (e.g. illumination of guard rings) or “feature of setup”



# FBK $^{90}\text{Sr}$ measurements (non-irradiated)



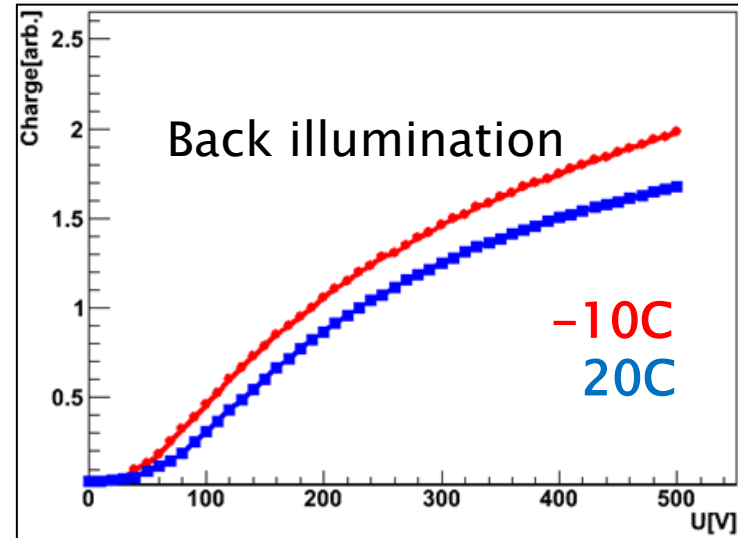
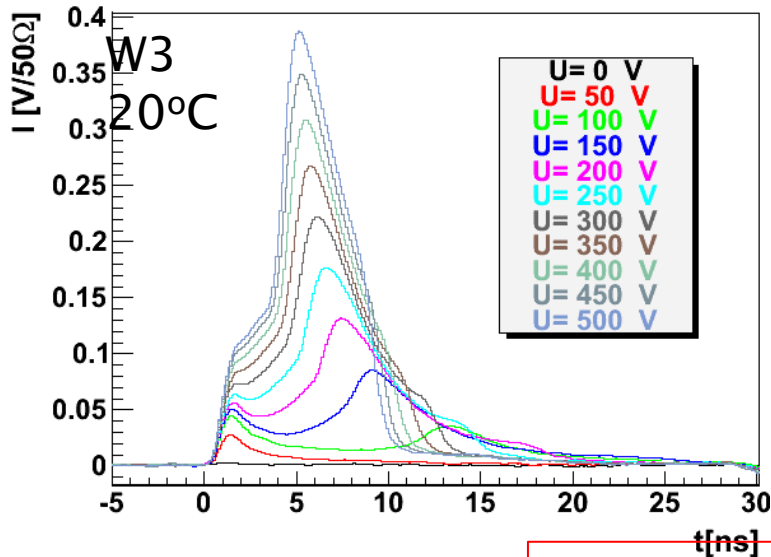
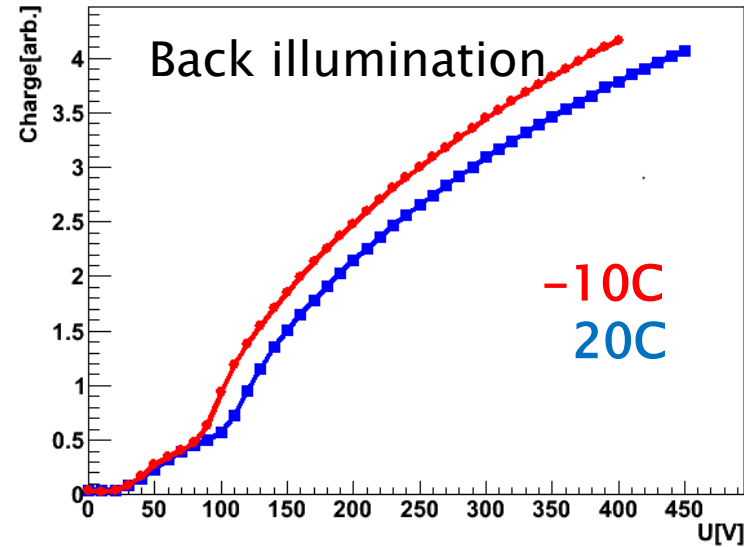
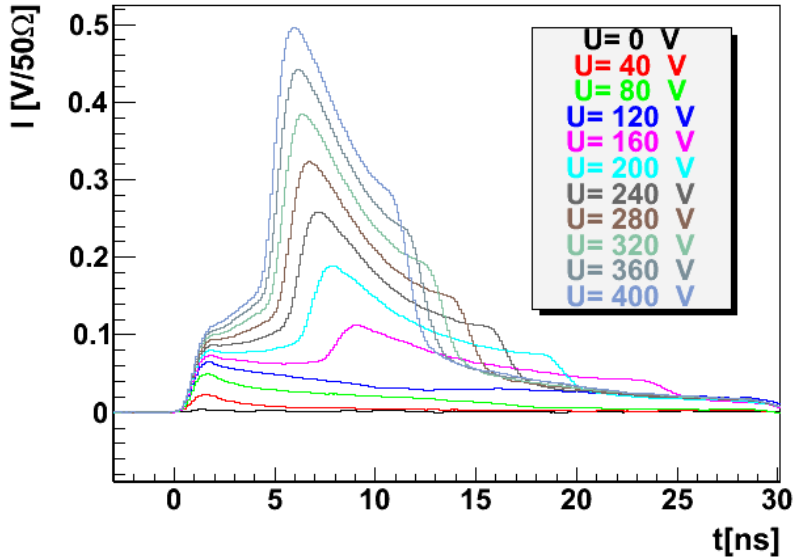
Small sample size is a problem as trigger purity is affected:

- ▶ events missing the sensor (Noise peak)
- ▶ guard ring collection ? (capacitively transferred charge to the collecting electrode)
- ▶ active area collection (multiplied signal)

Huge signals saturate the amplifier for W10 – break down ~500–600V

some discrepancy between  $G_{\text{TCT}}$  and  $G_{\text{MIP}}$

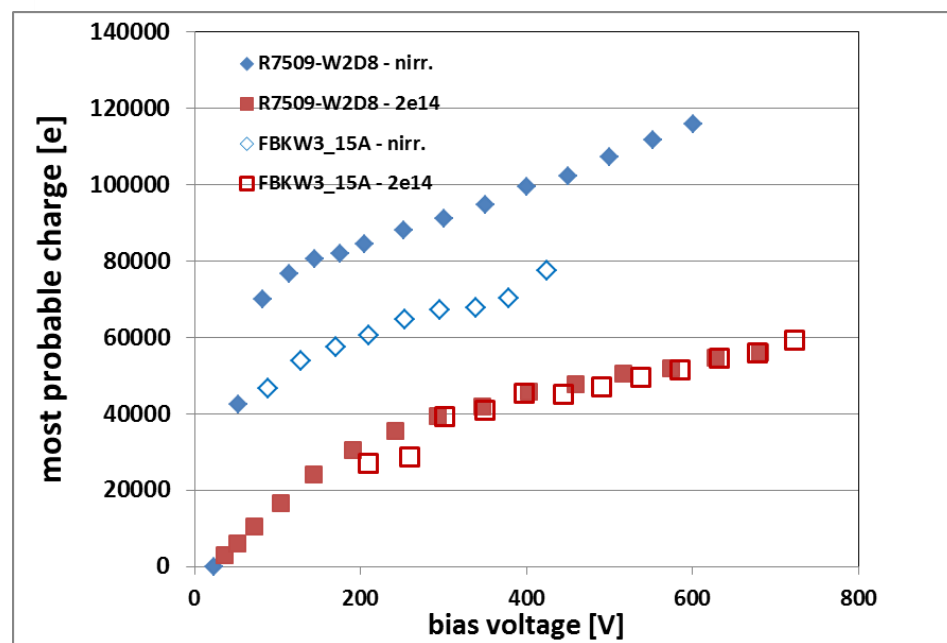
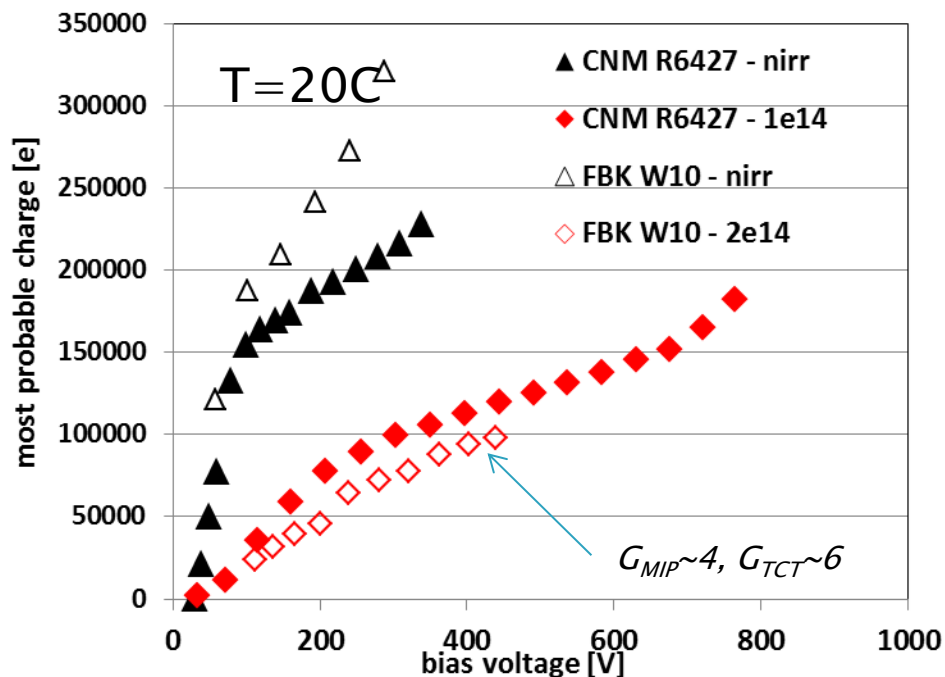
# TCT - W10 ( $2e14 \text{ cm}^{-2}$ )



- ▶ More negative space charge for W3 (expected)
- ▶ Q-V plot is not understood - why smaller slope at high bias
- ▶ Much smaller temperature dependence as before irradiation



# FBK - CCE with $^{90}\text{Sr}$ after $2e14 \text{ cm}^{-2}$



- ▶ Larger gain loss measured with  $G_{MIP}$  wrt. to  $G_{TCT}$  - under investigation
- ▶ Impure trigger complicated the analysis even more at smaller gain (difficult separation of peaks)

**Preliminary evaluation of FBK detectors performance in terms of gain seems to be comparable to CNM detectors.**

# Conclusions

- ▶ The gain degrades in CNM thin LGADs in accordance with expectations, but high bias voltage tolerance and residual acceptors in p+ layer may allow for successful timing applications.
- ▶ For fluences  $>2e15 \text{ cm}^{-2}$  the effects of p+ gain layer are not visible anymore (however the gain is still there)
- ▶ First FBK production of LGADs demonstrated working devices
- ▶ TCT and CCE measurements showed very high multiplication and excellent break down performance before irradiation.
- ▶ After irradiation loss of gain is comparable to CNM devices – a more systematic study is ongoing.